

课程大纲 COURSE SYLLABUS

1.	课程代码/名称 Course Code/Title	电子材料先进表征技术 Advanced Characterization Techniques for Electronic Materials
2.	课程性质 Compulsory/Elective	Elective
3.	课程学分/学时 Course Credit/Hours	1 学分/16 学时
4.	授课语言 Teaching Language	英语 English
5.	授课教师 Instructor(s)	Aung Ko Ko Kyaw
6.	先修要求 Pre-requisites	无
7.	教学目标 Course Objectives	
	To understand the various characterization techniques that can used for electronic materials To be able to apply these techniques in the analysis of electronic materials and research	
8.	教学方法 Teaching Methods	
	Lecture, Demonstration	
9.	教学内容 Course Contents	
	Section 1	Introduction and Fundamentals,
	Section 2	Surface and Structural Analysis
	Section 3	X-Ray Photoelectron Spectroscopy
	Section 4	Auger Electron Spectroscopy
	Section 5	Scanning Tunneling Microscopy
	Section 6	Atomic Force Microscopy
	Section 7	X-ray Diffraction and Synchrotron
	Section 8	Scanning Electron Microscopy
	Section 9	Transmission Electron Microscopy
	Section 10	Four-Point Probe and Conductivity Measurement
	
10.	课程考核 Course Assessment	
	Class Assignment and Participation (20%) Quiz (30%) Project (50%)	
11.	教材及其它参考资料 Textbook and Supplementary Readings	
	Sam Zhang, Lin Li, Ashok Kumar, Materials Characterization techniques, 1 st Edition	